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FORM PTO-1449 (Modified) LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)			Attorney Docket No.: 082666-000100US		Application No.: 09/388,265	
			Applicant: Jin-Kuo Ho, et al.			
			Filing Date: September 1, 1999		Group: 2811	
Reference Designation			U.S. PATENT DOCUMENTS			Page 1
Examiner Initial	Document No.	Date	Name	Class	Sub-class	Filing Date (If Appropriate)
AA	5,652,434	07/29/97	Nakamura et al.	257	13	-
<u>Vu</u> AB	5,739,554	04/14/98	Edmond et al.	257	103	-
FOREIGN PATENT DOCUMENTS						
	Document No.	Date	Country	Class	Sub-class	Translation (Yes/No)
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)						
<u>Vu</u> AC	Birks, N., et al. "Oxidation of pure metals", <i>Introduction to High Temperature Oxidation of Metals</i> , (Ch. 4), <i>no date</i> .					
<u>Vu</u> AD	Ryouichi, Uriu, et al., "Metal to Insulator Transition in $\text{Pd}_{1-x}\text{Li}_x\text{O}$ " <i>Journal of the Physical Society of Japan</i> , Vol. 60, No.7, July, 1991, pp. 2479-2480					
<u>Vu</u> AE	Roy, A., et al. "Electrical and Magnetic Characterization of $\text{Rh}_2\text{O}_3\text{-I}$ ", <i>Materials Research Bulletin</i> , Vol. 33, No. 4, pp. 547-551, 1998					
<u>Vu</u> AF	Kawazoe, Hiroshi, et al. "P-type electrical conduction in transparent thin films of $\text{CuAlO}_2$ ", <i>Nature</i> , Vol. 389, October 30, 1997, 939-942					
<u>Vu</u> AG	Mori, T., et al. "Schottky barriers and contact resistances on p-type GaN", <i>Appl. Phys. Lett.</i> 69(23) December 2, 1996, pp. 3537-3539					
<u>Vu</u> AH	Smith, L.L., et al. "Microstructure, electrical properties, and thermal stability of Au-based ohmic contacts to p-GaN", <i>Journal of Materials Research</i> , Vol. 12, No. 9, Sept. 1997, pp. 2249-2254					
<u>Vu</u> AI	Jarzebski, Z.M., "Nickel Oxide, NiO", <i>Oxide Semiconductors</i> , Pergamon Press, Oxford, New York, pp. 155-211, <i>no date</i>					
<u>Vu</u> AJ	Kudo, Atsushi, et al., " $\text{SrCu}_2\text{O}_2$ : A p-type conductive oxide with wide band gap", <i>Applied Physics Letters</i> , Vol. 73, No. 2, July 13, 1998, pp. 220-222					
EXAMINER HUNG K. JU			DATE CONSIDERED 09/13/01			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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